

<b>Notice of References Cited</b>	Application/Control No. 10/527,684	Applicant(s)/Patent Under Reexamination DE DINECHIN ET AL.	
	Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0000539	01-2004	Takikawa et al.	219/121.64
*	B	US-6,555,779	04-2003	Obana et al.	219/121.63
*	C	US-6,608,285	08-2003	Lefebvre et al.	219/137R
*	D	US-4,475,788	10-1984	Tomassini et al.	385/33
*	E	US-5,866,870	02-1999	Walduck, Robert Philip	219/121.45
*	F	US-6,388,227	05-2002	Dykhno et al.	219/121.6
*	G	US-2004/0232130	11-2004	Sonoda et al.	219/137.00R
*	H	US-6,034,343	03-2000	Hashimoto et al.	219/74
*	I	US-5,821,493	10-1998	Beyer et al.	219/121.46
*	J	US-2003/0038120	02-2003	Minamida et al.	219/121.64
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.